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What is "Embedded - Microcontrollers"?

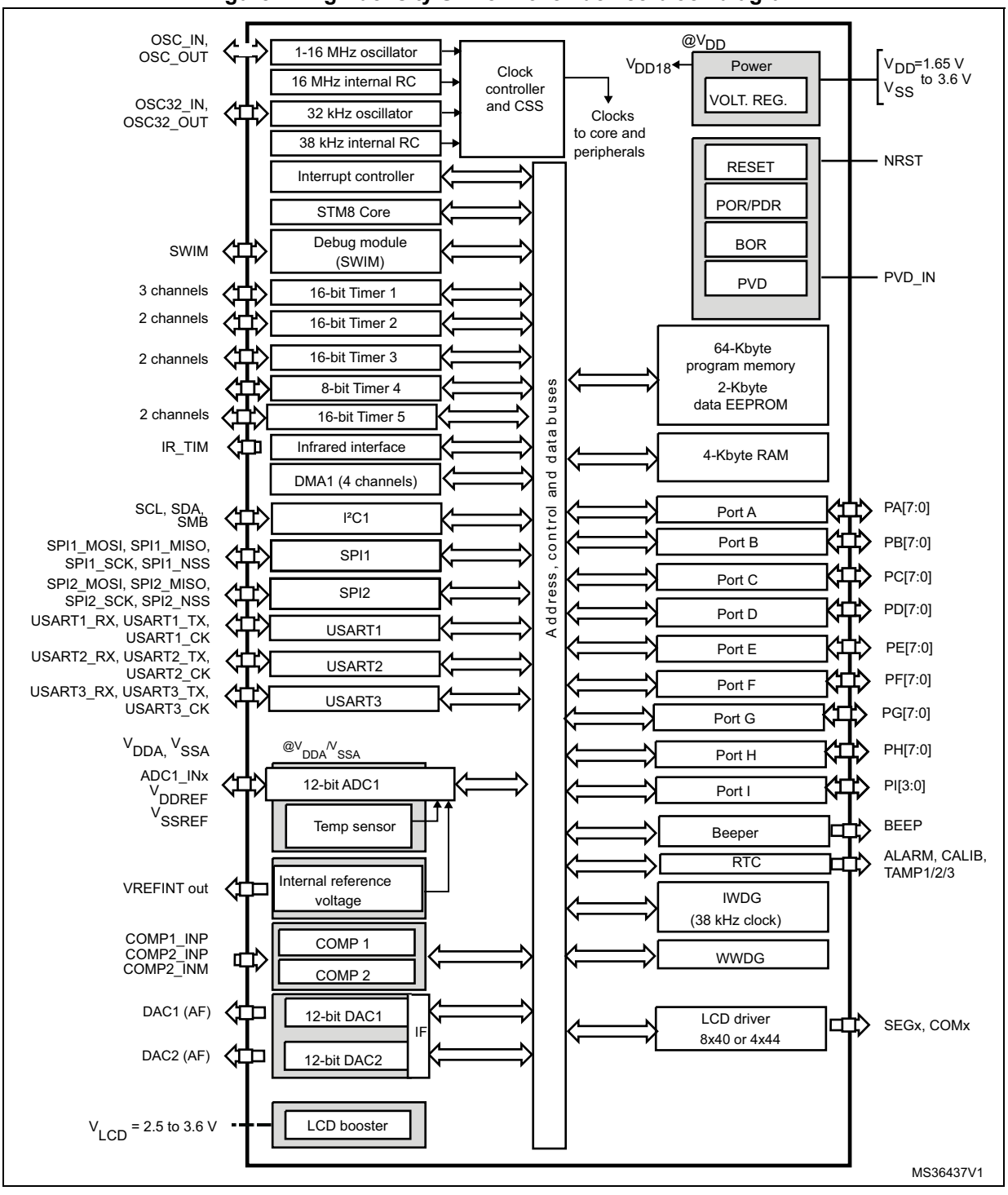
"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	41
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 25x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8al3188tcx

3 Functional overview

Figure 1. High-density STM8AL3x8x device block diagram



1. **Legend**: AF: alternate function
   ADC: Analog-to-digital converter

   BOR: Brownout reset
   DMA: Direct memory access

3.12 System configuration controller and routing interface

The system configuration controller provides the capability to remap some alternate functions on different I/O ports. TIM4 and ADC1 DMA channels can also be remapped.

The highly flexible routing interface allows application software to control the routing of different I/Os to the TIM1 timer input captures. It also controls the routing of internal analog signals to ADC1, COMP1, COMP2, DAC1 and the internal reference voltage V_{REFINT}. It also provides a set of registers for efficiently managing the charge transfer acquisition sequence.

3.13 Timers

The high-density STM8AL3x8x devices contain one advanced control timer (TIM1), three 16-bit general purpose timers (TIM2,TIM3 and TIM5) and one 8-bit basic timer (TIM4).

All the timers are served by DMA1.

Table 3 compares the features of the advanced control, general-purpose and basic timers.

Table 3. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA1 request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	up/down	Any integer from 1 to 65536	Yes	3 + 1	3
TIM2			Any power of 2 from 1 to 128		2	None
TIM3						
TIM5						
TIM4	8-bit	up	Any power of 2 from 1 to 32768		0	

3.13.1 16-bit advanced control timer (TIM1)

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down autoreload counter with 16-bit prescaler
- 3 independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output
- 1 additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- 3 complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.16 Communication interfaces

3.16.1 SPI

The serial peripheral interfaces (SPI1 and SPI2) provide half/ full duplex synchronous serial communication with external devices.

- Maximum speed: 8 Mbit/s (f_{SYSCLK}/2) both for master and slave
- Full duplex synchronous transfers
- Simplex synchronous transfers on 2 lines with a possible bidirectional data line
- Master or slave operation - selectable by hardware or software
- Hardware CRC calculation
- Slave/master selection input pin

Note: SPI1 and SPI2 can be served by the DMA1 Controller.

3.16.2 I^2C

The I^2C bus interface (I2C1) provides multi-master capability, and controls all I²C bus-specific sequencing, protocol, arbitration and timing.

- Master, slave and multi-master capability
- Standard mode up to 100 kHz and fast speed modes up to 400 kHz.
- 7-bit and 10-bit addressing modes.
- SMBus 2.0 and PMBus support
- Hardware CRC calculation

Note: I^2C1 can be served by the DMA1 Controller.

3.16.3 USART

The USART interfaces (USART1, USART2 and USART3) allow full duplex, asynchronous communications with external devices requiring an industry standard NRZ asynchronous serial data format. It offers a very wide range of baud rates.

- 1 Mbit/s full duplex SCI
- SPI1 emulation
- High precision baud rate generator
- Smartcard emulation
- IrDA SIR encoder decoder
- Single wire half duplex mode

Note: USART1, USART2 and USART3 can be served by the DMA1 Controller.

USART interfaces are used to implement LIN slave communication, with LIN Break detection on the framing error flag (FE in USART_SR register) with a value of 0 in the USART data register (USART_DR).

Table 5. High-density STM8AL3x8x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP80	LQFP64	LQFP48				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
58	46	-	PD5/TIM1_CH3 /LCD_SEG19(3)/ ADC1_IN9/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D5**	Timer 1 - channel 3 / LCD segment 19 / ADC1_IN9/Comparator 1 positive input
-	-	34	PD5/TIM1_CH3 /LCD_SEG19(3)/ ADC1_IN9/SPI2_MOSI/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D5**	Timer 1 - channel 3 / LCD segment 19 / ADC1_IN9/ SPI2 master out/slave in/Comparator 1 positive input
59	47		PD6/TIM1_BKIN /LCD_SEG20(3)/ ADC1_IN8/RTC_CALIB/ COMP1_INP/VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D6**	Timer 1 - break input / LCD segment 20 / ADC1_IN8 / RTC calibration/Comparator 1 positive input/Internal reference voltage output
-	-	35	PD6/TIM1_BKIN /LCD_SEG20(3)/ ADC1_IN8/RTC_CALIB/ SPI2_SCK/COMP1_INP/ VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D6**	Timer 1 - break input / LCD segment 20 / ADC1_IN8 / RTC calibration/SPI2 clock/Comparator 1 positive input/Internal reference voltage output
60	48	-	PD7/TIM1_CH1N /LCD_SEG21(3)/ ADC1_IN7/RTC_ALARM/ COMP1_INP/VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D7**	Timer 1 - inverted channel 1/ LCD segment 21 / ADC1_IN7 / RTC alarm/Comparator 1 positive input/Internal reference voltage output
-	-	36	PD7/TIM1_CH1N /LCD_SEG21(3)/ ADC1_IN7/RTC_ALARM/ SPI2_NSS/COMP1_INP/V REFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D7**	Timer 1 - inverted channel 1/ LCD segment 21 / ADC1_IN7 / RTC alarm /SPI2 master/slave select/Comparator 1 positive input/Internal reference voltage output
61	49	-	PG4/LCD_SEG32/ SPI2_NSS	I/O	FT(5)	**X**	X	X	HS	X	X	**Port G4**	LCD segment 32 / SPI2 master/slave select
62	50	-	PG5/LCD_SEG33/ SPI2_SCK	I/O	FT(5)	**X**	X	X	HS	X	X	**Port G5**	LCD segment 33 / SPI2 clock
63	51	-	PG6/LCD_SEG34/ SPI2_MOSI	I/O	FT(5)	**X**	X	X	HS	X	X	**Port G6**	LCD segment 34 / SPI2 master out- slave in

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 52B0	TIM1	TIM1_CR1	TIM1 control register 1	0x00
0x00 52B1		TIM1_CR2	TIM1 control register 2	0x00
0x00 52B2		TIM1_SMCR	TIM1 Slave mode control register	0x00
0x00 52B3		TIM1_ETR	TIM1 external trigger register	0x00
0x00 52B4		TIM1_DER	TIM1 DMA1 request enable register	0x00
0x00 52B5		TIM1_IER	TIM1 Interrupt enable register	0x00
0x00 52B6		TIM1_SR1	TIM1 status register 1	0x00
0x00 52B7		TIM1_SR2	TIM1 status register 2	0x00
0x00 52B8		TIM1_EGR	TIM1 event generation register	0x00
0x00 52B9		TIM1_CCMR1	TIM1 Capture/Compare mode register 1	0x00
0x00 52BA		TIM1_CCMR2	TIM1 Capture/Compare mode register 2	0x00
0x00 52BB		TIM1_CCMR3	TIM1 Capture/Compare mode register 3	0x00
0x00 52BC		TIM1_CCMR4	TIM1 Capture/Compare mode register 4	0x00
0x00 52BD		TIM1_CCER1	TIM1 Capture/Compare enable register 1	0x00
0x00 52BE		TIM1_CCER2	TIM1 Capture/Compare enable register 2	0x00
0x00 52BF		TIM1_CNTRH	TIM1 counter high	0x00
0x00 52C0		TIM1_CNTRL	TIM1 counter low	0x00
0x00 52C1		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 52C2		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 52C3		TIM1_ARRH	TIM1 Auto-reload register high	0xFF
0x00 52C4		TIM1_ARRL	TIM1 Auto-reload register low	0xFF
0x00 52C5		TIM1_RCR	TIM1 Repetition counter register	0x00
0x00 52C6		TIM1_CCR1H	TIM1 Capture/Compare register 1 high	0x00
0x00 52C7		TIM1_CCR1L	TIM1 Capture/Compare register 1 low	0x00
0x00 52C8		TIM1_CCR2H	TIM1 Capture/Compare register 2 high	0x00
0x00 52C9		TIM1_CCR2L	TIM1 Capture/Compare register 2 low	0x00
0x00 52CA		TIM1_CCR3H	TIM1 Capture/Compare register 3 high	0x00
0x00 52CB		TIM1_CCR3L	TIM1 Capture/Compare register 3 low	0x00
0x00 52CC		TIM1_CCR4H	TIM1 Capture/Compare register 4 high	0x00
0x00 52CD		TIM1_CCR4L	TIM1 Capture/Compare register 4 low	0x00
0x00 52CE		TIM1_BKR	TIM1 break register	0x00
0x00 52CF		TIM1_DTR	TIM1 dead-time register	0x00
0x00 52D0		TIM1_OISR	TIM1 output idle state register	0x00
0x00 52D1		TIM1_DCR1	DMA1 control register 1	0x00

Table 9. General hardware register map (continued)

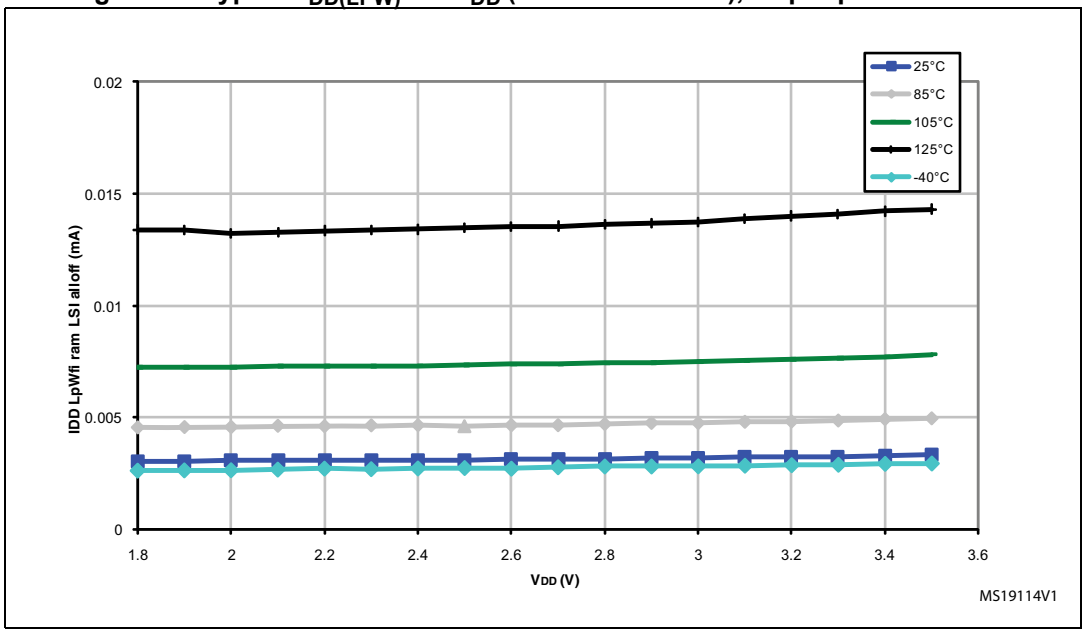
Address	Block	Register label	Register name	Reset status
0x00 53C8 to 0x00 53DF	Reserved area			
0x00 53E0	USART2	USART2_SR	USART2 status register	0xC0
0x00 53E1		USART2_DR	USART2 data register	0xXX
0x00 53E2		USART2_BRR1	USART2 baud rate register 1	0x00
0x00 53E3		USART2_BRR2	USART2 baud rate register 2	0x00
0x00 53E4		USART2_CR1	USART2 control register 1	0x00
0x00 53E5		USART2_CR2	USART2 control register 2	0x00
0x00 53E6		USART2_CR3	USART2 control register 3	0x00
0x00 53E7		USART2_CR4	USART2 control register 4	0x00
0x00 53E8		USART2_CR5	USART2 control register 5	0x00
0x00 53E9		USART2_GTR	USART2 guard time register	0x00
0x00 53EA		USART2_PSCR	USART2 prescaler register	0x00
0x00 53EB to 0x00 53EF	Reserved area			
0x00 53F0	USART3	USART3_SR	USART3 status register	0xC0
0x00 53F1		USART3_DR	USART3 data register	0xXX
0x00 53F2		USART3_BRR1	USART3 baud rate register 1	0x00
0x00 53F3		USART3_BRR2	USART3 baud rate register 2	0x00
0x00 53F4		USART3_CR1	USART3 control register 1	0x00
0x00 53F5		USART3_CR2	USART3 control register 2	0x00
0x00 53F6		USART3_CR3	USART3 control register 3	0x00
0x00 53F7		USART3_CR4	USART3 control register 4	0x00
0x00 53F8		USART3_CR5	USART3 control register 5	0x00
0x00 53F9		USART3_GTR	USART3 guard time register	0x00
0x00 53FA		USART3_PSCR	USART3 prescaler register	0x00
0x00 53FB to 0x00 53FF	Reserved area			

Table 24. Total current consumption in low-power wait mode at V_{DD} = 1.65 V to 3.6 V

Symbol	Parameter	Conditions(1)			Typ.	Max.	Unit
$I_{DD(LPW)}$	Supply current in low-power wait mode	LSI RC osc. (at 38 kHz)	all peripherals OFF	T_A = -40 °C to 25 °C	3.00	3.30(2)	µA
				T_A = 85 °C	4.40	9.00(3)	
				T_A = 125 °C	11.00	18.00(3)	
		LSE external clock(4) (32.768 kHz)		T_A = -40 °C to 25 °C	2.35	2.70(2)	
				T_A = 85 °C	3.10	3.70(2)	
				T_A = 125 °C	12.0	14.0(2)	

1. No floating I/Os.
2. Guaranteed by characterization results.
3. Tested at 85°C for temperature range A or 125°C for temperature range C.
4. Oscillator bypassed (LSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the LSE consumption ($I_{DD\ LSE}$) must be added. Refer to *Table 33*.

Figure 18. Typical $I_{DD(LPW)}$ vs. V_{DD} (LSI clock source), all peripherals OFF(1)



1. Typical current consumption measured with code executed from RAM.

Table 25. Total current consumption and timing in Active-halt mode at V_{DD} = 1.65 V to 3.6 V (continued)

Symbol	Parameter	Conditions(1)			Typ.	Max.(2)	Unit
$t_{WU\_HSI(AH)}$(9)(10)	Wakeup time from Active-halt mode to Run mode (using HSI)	-	-	-	4.70	7.00	µs
$t_{WU\_LSI(AH)}$(9)(10)	Wakeup time from Active-halt mode to Run mode (using LSI)	-	-	-	150.0	-	µs

1. No floating I/O, unless otherwise specified.
2. Guaranteed by characterization results.
3. RTC enabled. Clock source = LSI
4. RTC enabled, LCD enabled with external V_{LCD} = 3 V, static duty, division ratio = 256, all pixels active, no LCD connected.
5. RTC enabled, LCD enabled with external V_{LCD}, 1/4 duty, 1/3 bias, division ratio = 64, all pixels active, no LCD connected.
6. LCD enabled with internal LCD booster V_{LCD} = 3 V, 1/4 duty, 1/3 bias, division ratio = 64, all pixels active, no LCD connected.
7. Oscillator bypassed (LSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the LSE consumption ($I_{DD\ LSE}$) must be added. Refer to *Table 33*
8. RTC enabled. Clock source = LSE
9. Wakeup time until start of interrupt vector fetch.
   The first word of interrupt routine is fetched 4 CPU cycles after t_{WU}.
10. ULP=0 or ULP=1 and FWU=1 in the PWR_CSR2 register.

Table 26. Typical current consumption in Active-halt mode, RTC clocked by LSE external crystal

Symbol	Parameter	Condition(1)		Typ.	Unit
$I_{DD(AH)}$ (2)	Supply current in Active-halt mode	V_{DD} = 1.8 V	LSE	1.15	µA
			LSE/32(3)	1.05	
		V_{DD} = 3 V	LSE	1.30	
			LSE/32(3)	1.20	
		V_{DD} = 3.6 V	LSE	1.45	
			LSE/32(3)	1.35	

1. No floating I/O, unless otherwise specified.
2. Based on measurements on bench with 32.768 kHz external crystal oscillator.
3. RTC clock is LSE divided by 32.

Figure 19. Typical $I_{DD(AH)}$ vs. V_{DD} (LSI clock source)

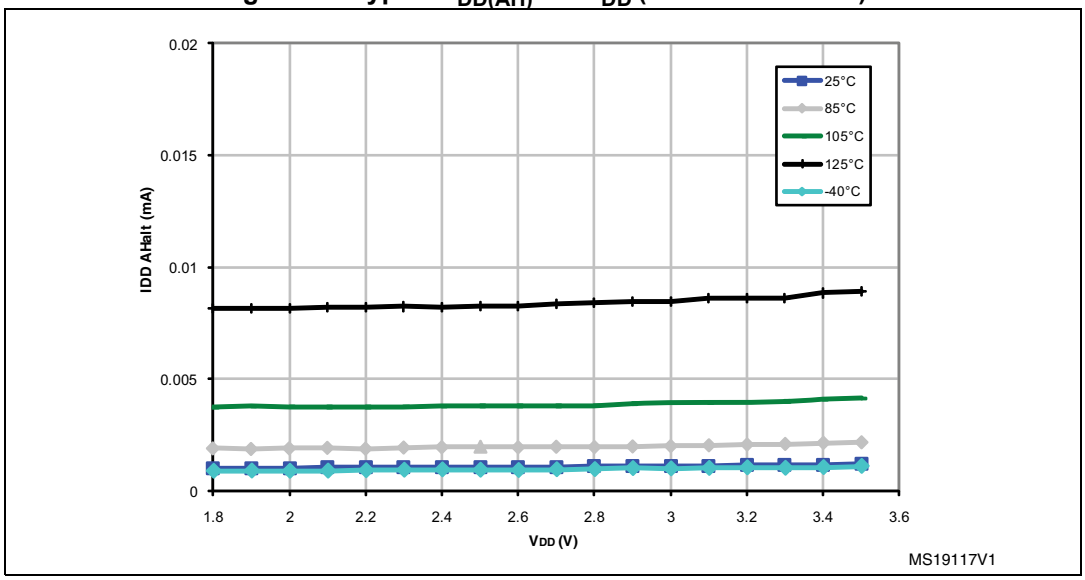
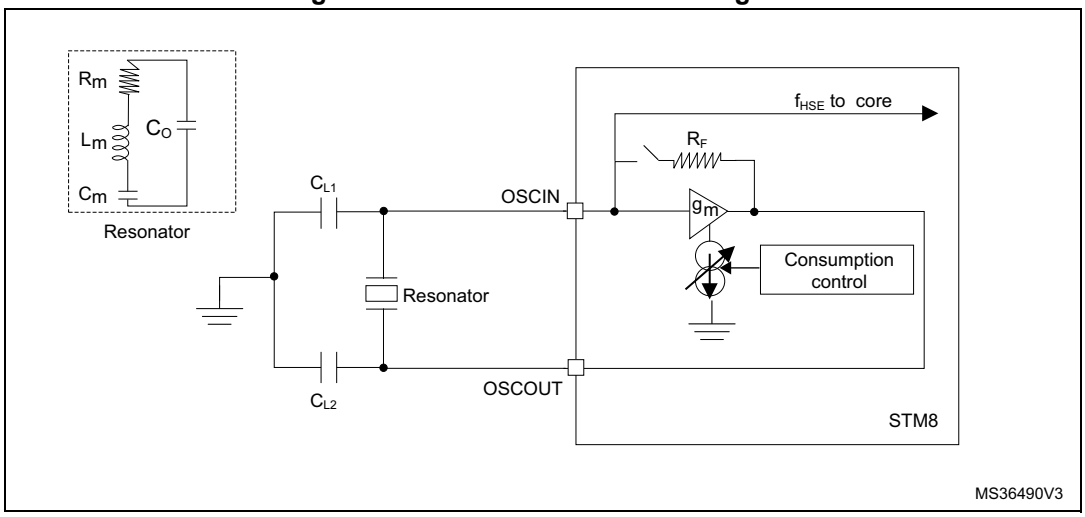


Figure 21. HSE oscillator circuit diagram



HSE oscillator critical g_m formula

$$g_{mcrit} = (2 \times \Pi \times f_{HSE})^2 \times R_m(2Co + C)^2$$

R_m: Motional resistance (see crystal specification), L_m: Motional inductance (see crystal specification), C_m: Motional capacitance (see crystal specification), Co: Shunt capacitance (see crystal specification), C_{L1}=C_{L2}=C: Grounded external capacitance

$g_m >> g_{mcrit}$

LSE crystal/ceramic resonator oscillator

The LSE is available on STM8AL318x devices only.

The LSE clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph is based on characterization results with specified typical external components. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details (frequency, package, accuracy...).

9.3.6 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error, out of spec current injection on adjacent pins or other functional failure (for example reset, oscillator frequency deviation, LCD levels, etc.).

The test results are given in the following table.

Table 40. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on true open-drain pins	-5	+0	mA
	Injected current on all 5 V tolerant (FT) pins	-5	+0	
	Injected current on any other pin	-5	+5	

9.3.7 I/O port pin characteristics

General characteristics

Subject to general operating conditions for V_{DD} and T_A unless otherwise specified. All unused pins must be kept at a fixed voltage: using the output mode of the I/O for example or an external pull-up or pull-down resistor.

Table 42. Output driving current (high sink ports)

I/O Type	Symbol	Parameter	Conditions	Min.	Max.	Unit
Standard	V_{OL} (1)	Output low-level voltage for an I/O pin	I_{IO} = +2 mA, V_{DD} = 3.0 V	-	0.45	V
			I_{IO} = +2 mA, V_{DD} = 1.8 V	-	0.45	V
			I_{IO} = +10 mA, V_{DD} = 3.0 V	-	0.7	V
	V_{OH} (2)	Output high-level voltage for an I/O pin	I_{IO} = -2 mA, V_{DD} = 3.0 V	V_{DD}-0.45	-	V
			I_{IO} = -1 mA, V_{DD} = 1.8 V	V_{DD}-0.45	-	V
			I_{IO} = -10 mA, V_{DD} = 3.0 V	V_{DD}-0.7	-	V

1. The I_{IO} current sunk must always respect the absolute maximum rating specified in *Table 16* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS}.
2. The I_{IO} current sourced must always respect the absolute maximum rating specified in *Table 16* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VDD}.

Table 43. Output driving current (true open drain ports)

I/O Type	Symbol	Parameter	Conditions	Min.	Max.	Unit
Open drain	V_{OL} (1)	Output low-level voltage for an I/O pin	I_{IO} = +3 mA, V_{DD} = 3.0 V	-	0.45	V
			I_{IO} = +1 mA, V_{DD} = 1.8 V	-	0.45	

1. The I_{IO} current sunk must always respect the absolute maximum rating specified in *Table 16* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS}.

Table 44. Output driving current (PA0 with high sink LED driver capability)

I/O Type	Symbol	Parameter	Conditions	Min.	Max.	Unit
IR	V_{OL} (1)	Output low-level voltage for an I/O pin	I_{IO} = +20 mA, V_{DD} = 2.0 V	-	0.45	V

1. The I_{IO} current sunk must always respect the absolute maximum rating specified in *Table 16* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS}.

Figure 29. Typical V_{OL} @ V_{DD} = 3.0 V (high sink ports)

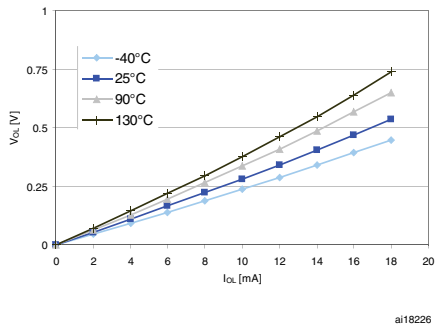


Figure 30. Typical V_{OL} @ V_{DD} = 1.8 V (high sink ports)

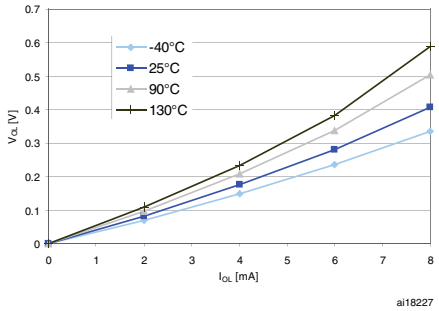


Figure 31. Typical V_{OL} @ V_{DD} = 3.0 V (true open drain ports)

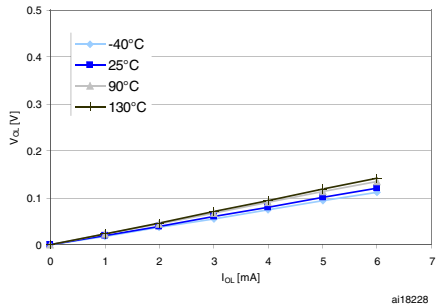


Figure 32. Typical V_{OL} @ V_{DD} = 1.8 V (true open drain ports)

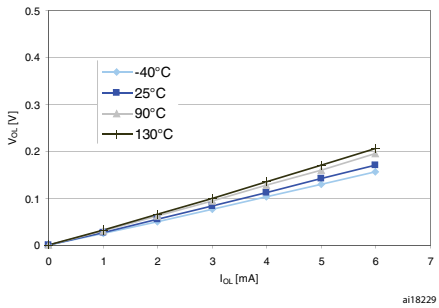


Figure 33. Typical V_{DD} - V_{OH} @ V_{DD} = 3.0 V (high sink ports)

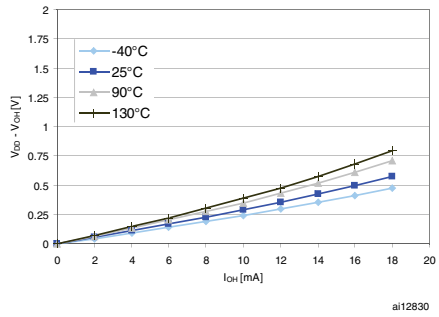
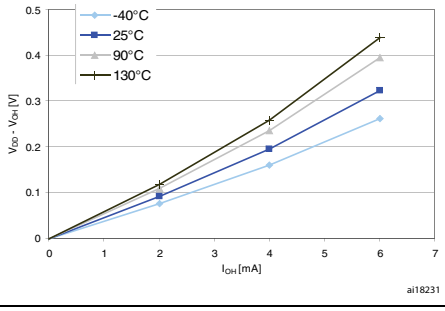


Figure 34. Typical V_{DD} - V_{OH} @ V_{DD} = 1.8 V (high sink ports)



NRST pin

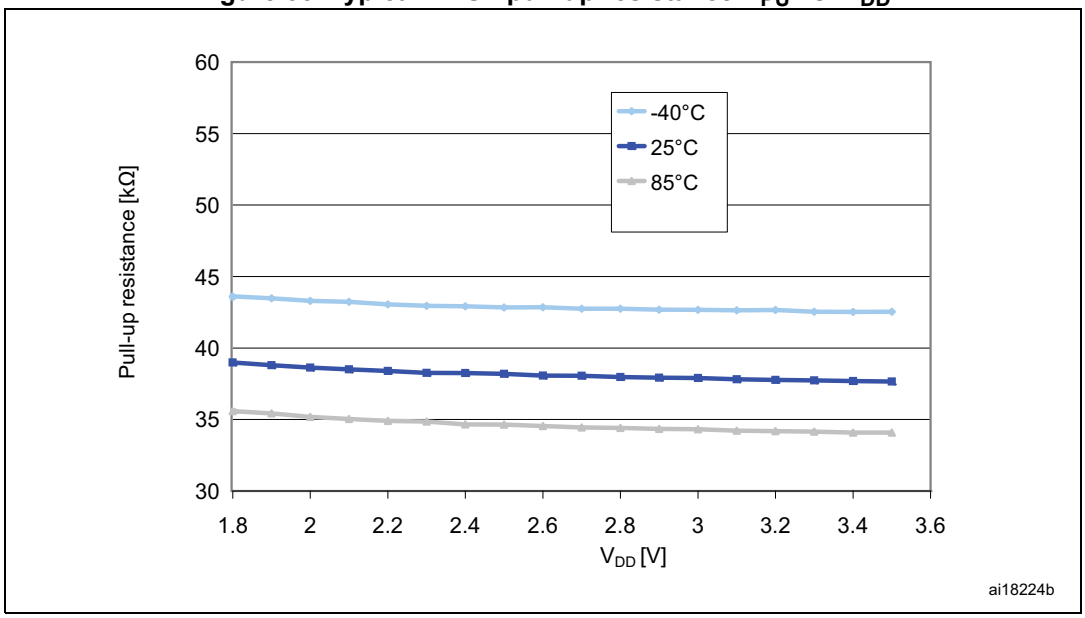
Subject to general operating conditions for V_{DD} and T_A unless otherwise specified.

Table 45. $\overline{\text{NRST}}$ pin characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$V_{IL(NRST)}$	NRST input low-level voltage	-	V_{SS}(1)	-	0.8(1)	V
$V_{IH(NRST)}$	NRST input high-level voltage (1)	-	1.4(1)	-	V_{DD}(1)	
$V_{OL(NRST)}$	NRST output low-level voltage (1)	I_{OL} = 2 mA for 2.7 V ≤V_{DD} ≤3.6 V	-	-	0.4(1)	
		I_{OL} = 1.5 mA for V_{DD} < 2.7 V	-	-		
V_{HYST}	NRST input hysteresis	-	10%V_{DD} (2)(3)	-	-	mV
$R_{PU(NRST)}$	NRST pull-up equivalent resistor	-	30(1)	45	60(1)	kΩ
$V_{F(NRST)}$	NRST input filtered pulse	-	-	-	50(3)	ns
$V_{NF(NRST)}$	NRST input not filtered pulse	-	300(3)	-	-	

1. Guaranteed by characterization results.
2. 200 mV min.
3. Guaranteed by design.

Figure 35. Typical NRST pull-up resistance R_{PU} vs. V_{DD}



9.3.8 Communication interfaces

SPI1 - Serial peripheral interface

Unless otherwise specified, the parameters given in *Table 46* are derived from tests performed under ambient temperature, f_{SYSCLK} frequency and V_{DD} supply voltage conditions summarized in *Section 9.3.1*. Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 46. SPI1 characteristics

Symbol	Parameter	Conditions(1)	Min.	Max.	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI1 clock frequency	Master mode	0	8	MHz
		Slave mode	0	8	
$t_{r(SCK)}$ $t_{f(SCK)}$	SPI1 clock rise and fall time	Capacitive load: C = 30 pF	-	30	ns
$t_{su(NSS)}$(2)	NSS setup time	Slave mode	4 x $1/f_{SYSCLK}$	-	
$t_{h(NSS)}$(2)	NSS hold time	Slave mode	80	-	
$t_{w(SCKH)}$(2) $t_{w(SCKL)}$(2)	SCK high and low time	Master mode, f_{MASTER} = 8 MHz, f_{SCK}= 4 MHz	105	145	
$t_{su(MI)}$(2) $t_{su(SI)}$(2)	Data input setup time	Master mode	30	-	
		Slave mode	3	-	
$t_{h(MI)}$(2) $t_{h(SI)}$(2)	Data input hold time	Master mode	15	-	
		Slave mode	0	-	
$t_{a(SO)}$(2)(3)	Data output access time	Slave mode	-	3x $1/f_{SYSCLK}$	
$t_{dis(SO)}$(2)(4)	Data output disable time	Slave mode	30	-	
$t_{v(SO)}$(2)	Data output valid time	Slave mode (after enable edge)	-	60	
$t_{v(MO)}$(2)	Data output valid time	Master mode (after enable edge)	-	20	
$t_{h(SO)}$(2)	Data output hold time	Slave mode (after enable edge)	15	-	
$t_{h(MO)}$(2)		Master mode (after enable edge)	1	-	

1. Parameters are given by selecting 10 MHz I/O output frequency.
2. Guaranteed by characterization results or by design.
3. Min. time is for the minimum time to drive the output and max. time is for the maximum time to validate the data.
4. Min. time is for the minimum time to invalidate the output and max. time is for the maximum time to put the data in Hi-Z.

Figure 44. Power supply and reference decoupling (V_{REF+} not connected to V_{DDA})

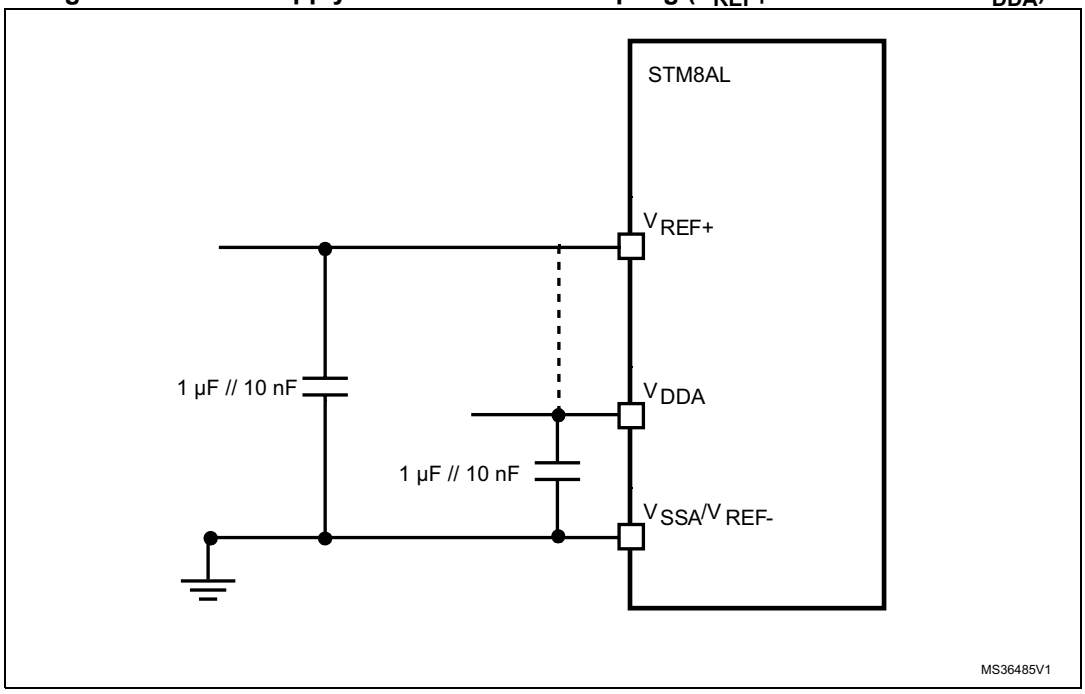


Figure 45. Power supply and reference decoupling (V_{REF+} connected to V_{DDA})

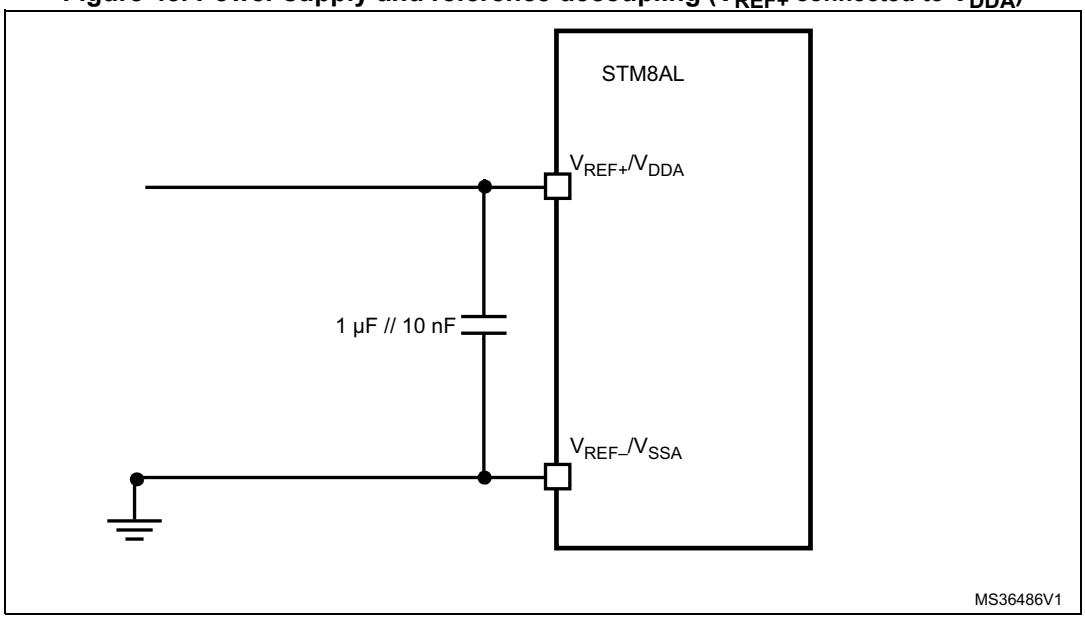
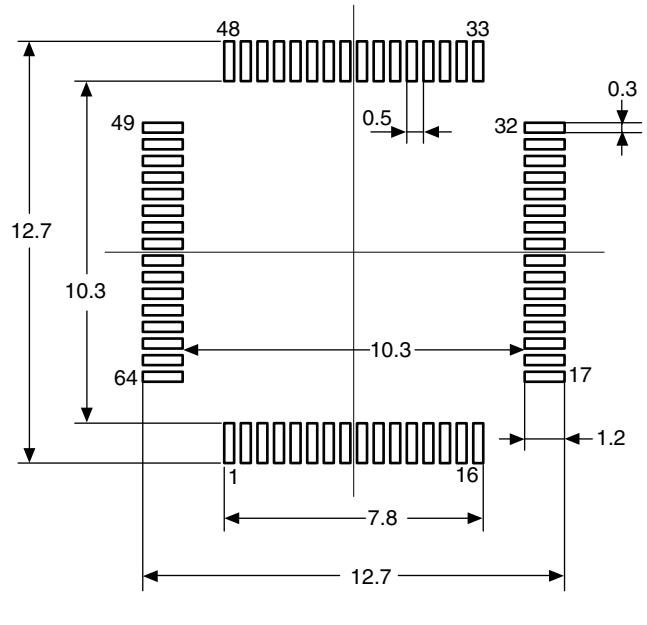


Table 66. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data (continued)

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

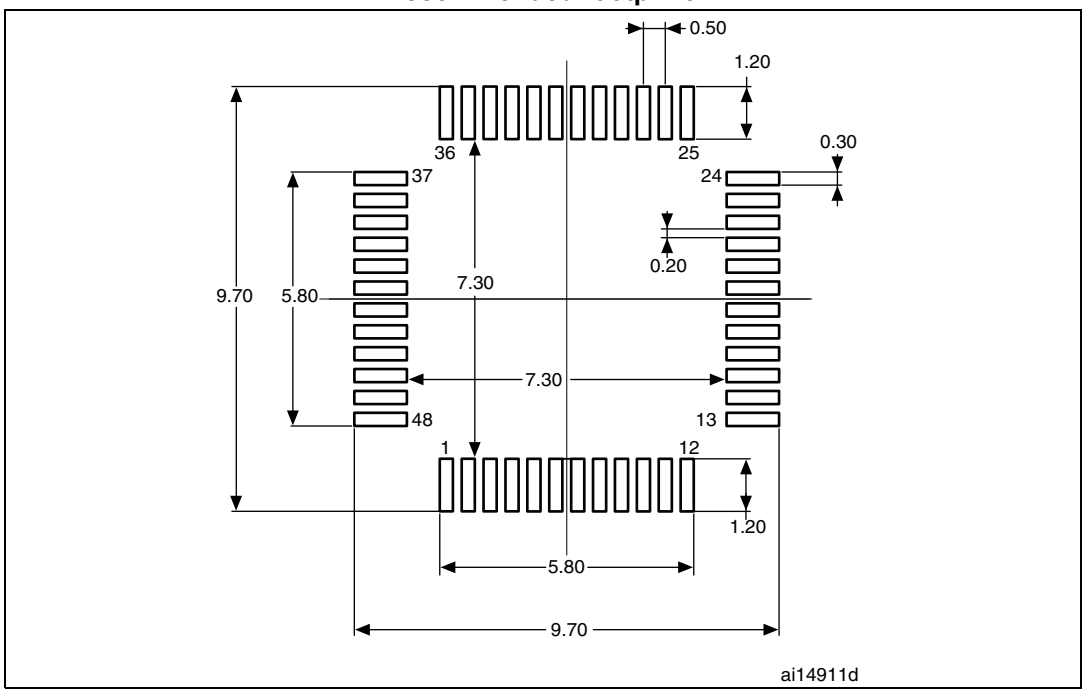
1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 50. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

Figure 53. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

12 Revision history

Table 69. Document revision history

Date	Revision	Changes
03-Feb-2015	1	Initial release.
22-Apr-2015	2	Added: – *Figure 50: LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package recommended footprint*, – *Figure 48: LQFP80 marking example (package top view)*, – *Figure 51: LQFP64 marking example (package top view)*, – *Figure 54: LQFP48 marking example (package top view)*. Corrected OPT0 default value in *Table 12: Option byte addresses*.
27-Jul-2015	3	Updated – the document confidentiality level to “Public”, – *Table 1: Device summary*, replacing STM8AL318AT with STM8AL318A.
19-Aug-2015	4	Datasheet status changed to “production data”.
1-Dec-2016	5	– Updated *Table 5: High-density STM8AL3x8x pin description*: two pin names changed from PI0/RTC_TAMP1/[SPI2_NSS]/[TIM3_CH3 to PI0/RTC_TAMP1/[SPI2_NSS]/[TIM3_CH1 and from PF2/ADC1_IN26/[SPI2_SCK]/[USART3_SCK] to PF2/ADC1_IN26/[SPI1_SCK]/[USART3_SCK] – Updated device marking part of *Section 10.1: LQFP80 package information*, *Section 10.2: LQFP64 package information* and *Section 10.3: LQFP48 package information* – Updated *Section 9.2: Absolute maximum ratings* – Updated table footnotes in *Chapter 9: Electrical parameters* – Updated *Figure 12: Power supply thresholds*
5-Dec-2016	6	– Updated *Table 5: High-density STM8AL3x8x pin description*: pin name changed from PC3/USART1_TX/LCD_SEG23(3)/ADC1_IN5/COMP_IN3M/COMP2_INM/COMP1_INP to PC3/USART1_TX/LCD_SEG23(3)/ADC1_IN5/COMP2_INM/COMP1_INP.